

**Search Notes**

Application/Control No.

10/626,369

Examiner

Anthony Weier

Applicant(s)/Patent under  
Reexamination

CHENG ET AL.

Art Unit

1761

**SEARCHED**

| Class   | Subclass           | Date       | Examiner |
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| updated | previous<br>search | 11/22/2005 | AW       |
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**INTERFERENCE SEARCHED**

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**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

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